

Influence of dephasing on shot noise in an electronic Mach-Zehnder interferometer

Florian Marquardt and C. Bruder

Departement Physik und Astronomie, Universität Basel, Klingelbergstr. 82, 4056 Basel, Switzerland

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We present a general analysis of shot noise in an electronic Mach-Zehnder interferometer, of the type investigated experimentally [Yang *et al.*, Nature 422, 415 (2003)], under the influence of dephasing produced by fluctuations of a classical field. We show how the usual partition noise expression $T(1-T)$ is modified by dephasing, depending on the power spectrum of the environmental fluctuations.

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A large part of mesoscopic physics is concerned with quantum interference effects in micrometer-size electronic circuits. Therefore, it is important to understand how interference is suppressed by the action of a fluctuating environment (such as phonons or other electrons), a phenomenon known as dephasing (or decoherence). In recent years, many experimental studies have been performed to learn more about the mechanisms of dephasing and its dependence on parameters such as temperature [1, 2, 3, 4, 5, 6, 7].

A delicate issue [4] in the analysis of interference effects other than weak localization is the fact that the “visibility” of the interference pattern can also be diminished by phase averaging: This takes place when electrons with a spread of wavelengths (determined by voltage or temperature) contribute to the current, or when some experimental parameter (such as path length) fluctuates slowly from run to run. Recently, a remarkable interference experiment has been performed using a Mach-Zehnder setup fabricated from the edge channels of a two-dimensional electron gas in the integer quantum hall effect regime [8]. Besides measuring the current as a function of the phase difference between the paths, the authors also measured the shot noise to distinguish between phase averaging and “real” dephasing. The basic idea is that both phenomena suppress the interference term in the current, but they may affect differently the partition noise which is nonlinear in the transmission probability. The idea of using shot noise to learn more about dephasing is promising, connecting two fundamental issues in mesoscopic physics.

Most theoretical works on dephasing in mesoscopic interference setups are concerned with its influence on the average current only (see Refs. 9, 10, 11, 12, 13, 14 and references therein), although there have been studies of shot noise in this context [15]. In this paper, we present the first analysis of shot noise for an electronic one-channel Mach-Zehnder interferometer under the influence of dephasing. We will consider dephasing produced by fluctuations of a classical potential, which describe either true nonequilibrium radiation impinging on the system or the thermal part of the environmental noise. This approach has been employed quite often in the past [11, 16],

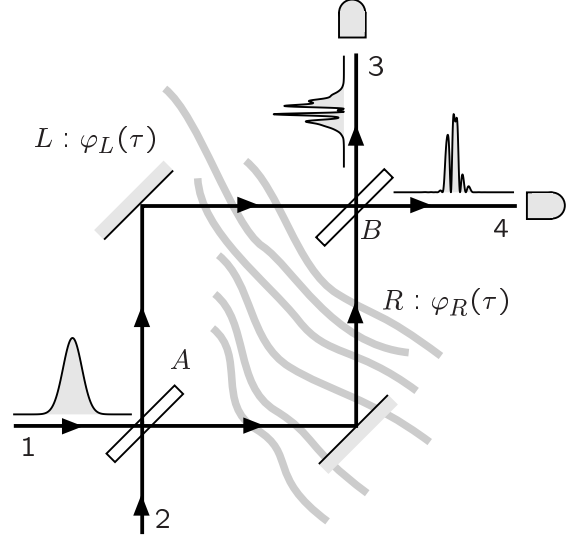


Figure 1: The Mach-Zehnder interferometer setup analyzed in the text. In the case shown here, the fluctuations of the environment are fast compared with the temporal extent of the wave packet (determined by temperature or voltage, see text). The probability density of the incoming wave packet and its two outgoing parts is shown.

is exact in the first case, and should be a reliable approximation for $T \ll eV$ in the second case. In particular, we are interested in the influence of the power spectrum of the environmental fluctuations on the shot-noise result, a question that goes beyond the phenomenological dephasing terminal model [15, 17, 18, 19, 20].

Model and general results. - We consider non-interacting, spin-polarized electrons. By solving the Heisenberg equation of motion for the electron field $\hat{\psi}$ moving at constant velocity v_F (linearized dispersion relation) and under the action of a fluctuating potential $V(\mathbf{x};t)$ (without backscattering), we obtain

$$\hat{\psi}(\mathbf{x};t) = \int \frac{d\mathbf{k}}{2\pi} e^{i\mathbf{k}\cdot\mathbf{x}} \sum_{\mathbf{k}'} \int_0^t dt' \langle \mathbf{k}; t' | \hat{a}(\mathbf{k}) e^{i\mathbf{k}_F \cdot \mathbf{x}} \rangle \quad (1)$$

for the electron operator at the output port 3. We have

$t_3 = 1$, $s_{1,2} = 1$; $s_3 = -1$, the reservoir operators obey $\hat{a}^\dagger(\mathbf{k})\hat{a}(\mathbf{k}^0) = \delta(\mathbf{k} - \mathbf{k}^0)f(\mathbf{k})$, and the integration is over $\mathbf{k} > 0$ only. The amplitudes t_1, t_2 for an electron to go from terminal 1 or 2 to the output terminal 3 are time-dependent:

$$t_1(\mathbf{k}; \tau) = t_A t_B e^{i\tau_{L,R}} + r_A r_B e^{i\tau_{L,R}} e^{i(\mathbf{k} + \mathbf{k}^0) \cdot \mathbf{x}} \quad (2)$$

$$t_2(\mathbf{k}; \tau) = t_A r_B e^{i\tau_{L,R}} e^{i(\mathbf{k} + \mathbf{k}^0) \cdot \mathbf{x}} + r_A t_B e^{i\tau_{L,R}} \quad (3)$$

Here $t_{A=B}$ and $r_{A=B}$ are energy-independent transmission and reflection amplitudes at the two beamsplitters ($t_j r_j = t_j r_j$), \mathbf{x} is a possible path-length difference, and τ the Aharonov-Bohm phase due to the flux through the interferometer. The electron accumulates fluctuating phases while moving along the left or right arm: $\tau_{L,R}(\tau) = \int_0^{\tau} dt \mathbf{v}(\mathbf{x}_{L,R}(t)) \cdot \mathbf{p}$, where τ is the time when the electron leaves the second beamsplitter after traveling for a time $\tau_{L,R}$ along $\mathbf{x}_{L,R}$. Note that in our model the total traversal times $\tau_{L,R}$ enter only at this point.

The output current following from (1) has to be averaged over the fluctuating phases, i.e. it depends on phase-averaged transmission probabilities $T_1 = \langle t_1^2 \rangle$ and $T_2 = 1 - T_1$:

$$\langle I \rangle = T_A T_B + R_A R_B + 2z (r_A r_B) t_A t_B \cos(\mathbf{k} + \mathbf{k}^0) \cdot \mathbf{x}; \quad (4)$$

The interference term is suppressed by $z = e^{i\tau}$, (with $\tau = \tau_L - \tau_R$), which is $\exp(-\tau^2/2)$ for Gaussian τ . This decreases the visibility of the interference pattern observed in $I(\tau)$. However, such a suppression can also be brought about by the \mathbf{k} -integration, if $\mathbf{x} \neq 0$ (thermal smearing).

Our main goal is to calculate the shot noise power S at zero frequency. It can be split into two parts:

$$S = \int d\tau \langle \hat{I}(\tau) \hat{I}(0) \rangle + \int d\tau \langle \hat{I}(\tau) \hat{I}(0) \rangle + \int d\tau \langle \hat{I}(\tau) \hat{I}(0) \rangle \quad (5)$$

The first integral on the r.h.s. describes shot noise due to the temporal fluctuations of the conductance, i.e. fluctuations of a classical current $I(\tau) = \langle \hat{I}(\tau) \rangle$ depending on time-dependent transmission probabilities. We denote its noise power as S_{cl} . It rises quadratically with the total current, as is known from 1=f-noise in mesoscopic conductors [21].

The second integral is evaluated by inserting (1) and applying Wick's theorem:

$$\langle \hat{I}(\tau) \hat{I}(0) \rangle = \frac{e v_F}{2} \int d\mathbf{k} d\mathbf{k}^0 \sum_{j=1,2,3} f(\mathbf{k}) (1 - f(\mathbf{k}^0)) K(\tau) e^{i(\mathbf{k}^0 - \mathbf{k}) \cdot \mathbf{x}}; \quad (6)$$

Here K is a correlator of four transmission amplitudes: We have $K_{33} = 1$, $K_{31} = K_{13} = 0$, and

$$K(\tau) = \langle t_1(\mathbf{k}; \tau) t_1(\mathbf{k}^0; \tau) t_2(\mathbf{k}; 0) t_2(\mathbf{k}^0; 0) \rangle; \quad (7)$$

for $j = 1, 2$.

In order to obtain two limiting forms of this expression, we note that the τ -range of the oscillating exponential factor under the integral in (6) is determined by the Fermi functions, i.e. by voltage and temperature. This has to be compared with the correlation time τ_c of the environment (the typical decay time of the phase correlator $\langle \hat{I}(\tau) \hat{I}(0) \rangle$). For $eV_c \ll 1$ and $T \ll \tau_c$ ("fast environment"), the major contribution of the integration comes from $j = j_c$, where K factorizes into

$$K(\tau) = K(1) \langle t_1(\mathbf{k}; 0) t_1(\mathbf{k}^0; 0) \rangle; \quad (8)$$

This yields the noise power

$$\frac{S_{fast}}{e^2 v_F} = \int d\mathbf{k} \sum_{j=1,2} f(1 - f) \langle t_j(\mathbf{k}; 0) t_j(\mathbf{k}^0; 0) \rangle; \quad (9)$$

where we have set $f_j = f(\mathbf{k})$ and $t_j = t_j(\mathbf{k}; 0)$. We conclude that the shot noise for a "fast" environment is *not* given by a simple expression of the form $\langle I \rangle (1 - \langle I \rangle)$, since we have

$$\langle t_1 t_2 \rangle \neq \langle t_1 \rangle (1 - \langle t_1 \rangle) = (z^2 - 1) R_B T_B; \quad (10)$$

The remainder of the noise power from Eq. (6) (with $K(\tau) = K(1)$ inserted in Eq. (6)) will be denoted S_{fluct} . It yields a contribution to the Nyquist noise $S_{V=0}$, but apart from that it becomes important only

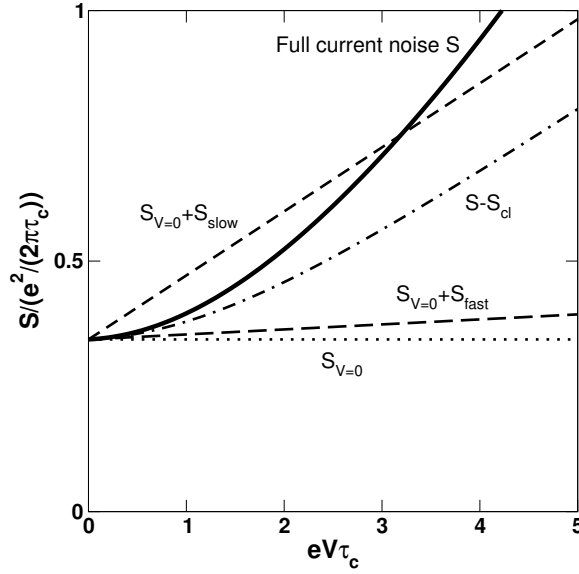


Figure 2: Typical behaviour of the full current noise S as a function of eV/ϵ_c . At higher voltages, the dependence on V is quadratic, due to S_{cl} . When S_{cl} is subtracted, the slope at large eV/ϵ_c is determined by S_{slow} (i.e. $\hbar T_1(1 - T_1)i$), while that at low voltages is always determined by S_{fast} (i.e. $\hbar t_1 t_2 i$). Parameters: $T = 0$, $x = 0$, $\epsilon = 0$, $T_A = 1/2$, $z = 1/e$, $T_B = 0.4$.

at larger V ; T . With this definition, the full noise power can be written as

$$S = S_{fast} + S_{fluct} + S_{cl}; \quad (11)$$

which is valid over the entire parameter space.

In the other limiting case, when the ω -integration is dominated by $j \approx j_c$ (“slow environment”), we can use $K(\omega) \approx K(0)$, which yields

$$\frac{S_{slow}}{e^2 V_F/2} = \int_0^{\infty} dk \hbar(f_1 T_1 + f_2 T_2) (1 - (f_1 T_1 + f_2 T_2)) i; \quad (12)$$

i.e. the phase-average of the usual shot noise expression (at $T = 0$ the integrand is $\hbar T_1(1 - T_1)i$).

Discussion. - We are able to evaluate the phase-averages if the potential $V(\mathbf{x};t)$ (and therefore ϕ') is assumed to be a Gaussian random field of zero mean. In the following, we present explicit expressions for the case $T = 0$, $x e V_F = 1$, where the visibility is decreased purely by dephasing. We can express the results by the following Fourier transforms that depend on the power spectrum of the fluctuations and are nonperturbative in the fluctuating field ($\epsilon = 0$):

$$\hat{g}(\omega) = \int_0^{\infty} d\epsilon e^{i\omega\epsilon} \langle e^{h'(\epsilon)} \phi'(0) i \rangle; \quad (13)$$

$$I(\omega) = \int_0^{\infty} d\epsilon (1 - \frac{i}{eV}) \hat{g}(\omega) \quad (14)$$

The shot noise becomes ($\sim = + k_F x$):

$$\begin{aligned} \frac{S - S_{V=0}}{e^2 V_F/2} &= \frac{eV}{z^2 R_A R_B T_A T_B} (\cos(2\omega) \hat{g}(\omega) + \hat{g}_+(\omega)) \\ &+ \hbar t_1 t_2 i \omega^2 \\ &+ \frac{1}{z^2 R_B T_B} \int_0^{\infty} d\epsilon \cos(2\omega\epsilon) R_A T_A I(\omega) \\ &+ (R_A^2 + T_A^2) I_+(\omega) \end{aligned} \quad (15)$$

The first line corresponds to S_{cl} , the second to S_{fast} , and the rest to S_{fluct} at $S_{V=0}$. At $V \rightarrow 0$, the integrals $I(\omega)$ vanish and S_{fast} dominates. At large $eV/\epsilon_c \gg 1$ we can use the sum-rule $I(\omega) \approx \frac{1}{z^2} \int_0^{\infty} d\epsilon \cos(2\omega\epsilon) = 1$ and find the last three lines to combine to $\hbar T_1(1 - T_1)i$, i.e. S_{slow} . The Nyquist noise is ω -independent:

$$S_{V=0} = \frac{e^2}{2} z^2 R_B T_B \int_0^{\infty} d\omega \langle \hat{g}_+(\omega) \rangle; \quad (16)$$

The results are illustrated in Figs. 2 and 3, where the evolution of S with increasing voltage V shows the cross-over between a “fast” and a “slow” environment. Although S_{fast} can become zero, the total current noise S does not vanish, due to the Nyquist contribution. The plots have been produced by assuming 50% transparency of the first beamsplitter ($T_A = 1/2$) and using a simple Gaussian form for the phase correlator:

$$\langle h'(\epsilon) h'(\epsilon') \phi'(0) i \rangle = \epsilon'^2 e^{-(\epsilon - \epsilon')^2}; \quad (17)$$

An application of the general theory presented here to specific situations includes the calculation of the phase-correlator, starting from the correlator describing the potential fluctuations $V(\mathbf{x};t)$ (cf. [11] for an example).

If shot noise is to be used as a tool to distinguish phase averaging from ‘genuine dephasing’, it is important to inquire about the form of shot noise for a situation in which both effects are present. In particular, for a large path-length difference $x = V_F = eV$ (relevant for the experiment of Ref. [8]), or $x = V_F = T$, the interference term is already suppressed completely due to wavelength averaging. Then S_{cl} vanishes, since $\hat{f}(\omega)$ is independent of the fluctuating phase. In addition, we find (at $T = 0$):

$$\begin{aligned} \frac{S - S_{V=0}}{e^2 V_F/2} &= T_A R_A (T_B - R_B)^2 + \\ &z^2 T_B R_B (T_A^2 + R_A^2) [1 + \frac{I_+(\omega)}{e^2 V_F/2}]; \end{aligned} \quad (18)$$

For a “fast” environment, we have $I_+(\omega) \rightarrow 0$, such that Eq. (18) becomes $(T_B - R_B)^2 + 2z^2 R_B T_B = 4$, which

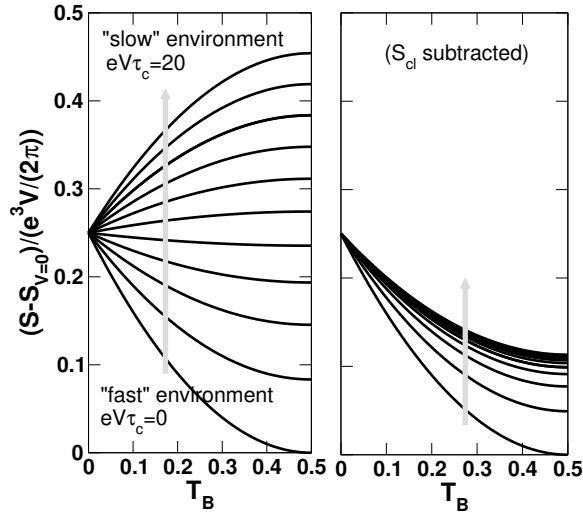


Figure 3: Normalized shot noise $(S - S_{V=0}) / (e^3 V / (2\pi))$ as a function of the transmission T_B of the second beamsplitter for small visibility ($z = 1/e$). The different curves show the succession from a “fast” environment to a “slow” one (bottom to top : $eV\tau_c = 0; 2; 4; \dots; 20$). In the right panel, the contribution from S_{cl} (first line of (15)) has been dropped, to demonstrate the convergence against the result for a slow bath, $\hbar T_1 / (1 - T_1)$ (topmost curve). Other parameters as in Fig. 2.

turns into $(T_B - R_B)^2 = 4$ for $z \neq 0$. This could be distinguished from the k -averaging result, but it corresponds to the case of large energy transfers from and to the environment (as opposed to “pure dephasing”). On the other hand, in the limit of large voltages (“slow environment”, $eV\tau_c \gg 1$), we have $T_+ \approx 1 - z^2/2$, and Eq. (18) turns into $(T_B^2 + R_B^2) = 4$, which is equal to the result obtained for pure k -averaging (without any additional dephasing).

We have pointed out already that neither S_{fast} nor S_{slow} lead to the simple result $\hbar T_1 / (1 - T_1)$. However, this form does indeed apply if we consider injecting only a “narrow beam” of electrons into terminal 1 (i.e. $f(k) = 0$ except for $f_1(k) = 1$ within $[k_F; k_F + eV/v_F]$), which is not equivalent to the previous situation regarding shot noise (cf. [22] in this respect). We get for $eV\tau_c \gg 1$:

$$S - S_{cl} = \frac{e^3 V}{2} \frac{\hbar T_1}{1 - T_1}; \quad (19)$$

while the case $eV\tau_c \ll 1$ is described by S_{slow} .

Comparison with other models. - Finally, we compare our results in the fully incoherent limit ($z = 0$) with two other models, namely the phenomenological dephasing terminal [15, 19, 20], and a simple model of a stream of regularly injected electrons [23] that reach the output port with a probability calculated according to classical rules. We focus on $T = 0$ and the case $T_A = 1/2$.

At small path-length difference $eV \ll \hbar\tau_c^{-1}$ (no k -averaging), we obtain $\hbar T_1 / (1 - T_1) = 1/4$ both for the classical model and the narrow beam of electrons, $(T_B - R_B)^2 = 4$ for our shot-noise expression in the “fast” case, and $(T_B^2 + R_B^2) = 4$ both for the “slow” case and from the dephasing terminal [24]. In the opposite limit of large $eV\tau_c$ only the result for the classical model changes, coinciding with the “slow” case $(T_B^2 + R_B^2) = 4$, which is also obtained without any dephasing. Therefore, in this regime a shot noise measurement most likely will not be able to reveal the additional presence of dephasing.

In conclusion, we have derived shot-noise expressions for an experimentally relevant model of an electronic Mach-Zehnder interferometer under the influence of dephasing by a classical fluctuating potential. The dependence of the shot noise on the power spectrum of the fluctuations has been analyzed, demonstrating a crossover between two regimes. We have pointed out that a shot-noise measurement cannot reveal the presence of dephasing on top of thermal averaging, for environmental fluctuations slower than the inverse voltage or temperature. The present theory may be applied to other interferometer geometries as well, even in the presence of backscattering at junctions.

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